

# PESD2ETH1GT-Q

## ESD protection for in-vehicle networks

29 March 2023

**Product data sheet** 

#### 1. General description

Fully OPEN Alliance 100BASE-T1 and 1000BASE-T1 compliant Electrostatic Discharge (ESD) protection device in a small SOT23 surface-mounted plastic package, designed to protect two automotive in-vehicle network bus lines from the damage caused by ESD and other transients.

#### 2. Features and benefits

- Fully OPEN Alliance 100BASE-T1 and 1000BASE-T1 compliant
- High trigger voltage: V<sub>t1</sub> = 100 V min.
- Low capacitance: C<sub>d</sub> < 2 pF</li>
- ESD protection up to 30 kV (IEC 61000-4-2)
- 1000 contact discharges (OPEN Alliance specification) with 15 kV (IEC 61000-4-2)
- Qualified according to AEC-Q101 and recommended for use in automotive applications

### 3. Applications

ESD protection for in-vehicle network lines in automotive environments

- OPEN Alliance 100/1000BASE-T1 Ethernet
- Low-Voltage Differential Signaling (LVDS) automotive

#### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>RWM</sub>	reverse standoff voltage	T <sub>amb</sub> = 25 °C		-	-	24	V
C <sub>d</sub>	diode capacitance	f = 1 MHz; V <sub>R</sub> = 0 V; T <sub>amb</sub> = 25 °C		-	1.8	2	pF
V <sub>t1</sub>	trigger voltage	t <sub>p</sub> = 100 ns; T <sub>amb</sub> = 25 °C	[1]	100	130	-	V
V <sub>ESD</sub>	electrostatic discharge	IEC 61000-4-2; contact discharge	[2] [3]	30	-	-	kV
	voltage	1000 contact discharges (IEC 61000-4-2); OPEN Alliance specification	[3]	15	-	-	kV

- [1] Non-repetitive current pulse, Transmission Line Pulse (TLP); square pulse; ANSI / ESD STM5.5.1-2008
- [2] Device stressed with ten non-repetitive ESD pulses.
- [3] Measured from pin 1 or 2 to pin 3.



## 5. Pinning information

#### **Table 2. Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	3	
2	K	cathode		к1 Д Д
3	СС	common cathode	SOT23	CC 006aaa155

## 6. Ordering information

#### **Table 3. Ordering information**

Type number	Package		
	Name	Description	Version
PESD2ETH1GT-Q	SOT23	plastic, surface-mounted package; 3 terminals; 1.9 mm pitch; 2.9 mm x 1.3 mm x 1 mm body	SOT23

## 7. Marking

#### Table 4. Marking codes

Type number	Marking code[1]
PESD2ETH1GT-Q	%HK

[1] % = placeholder for manufacturing site code

## 8. Limiting values

#### Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134)

Symbol	Parameter	Conditions		Min	Max	Unit
I <sub>PPM</sub>	rated peak pulse current	t <sub>p</sub> = 8/20 μs	[1] [2]	-	2.3	Α
Tj	junction temperature			-	150	°C
T <sub>amb</sub>	ambient temperature			-55	150	°C
T <sub>stg</sub>	storage temperature			-65	150	°C
V <sub>ESD</sub>	electrostatic discharge voltage	IEC 61000-4-2; contact discharge	[3] [2]	30	-	kV
		ISO 10605; contact discharge; C = 150 pF; R = 330 $\Omega$	[3] [2]	30	-	kV
		ISO 10605; contact discharge; C = 330 pF; R = 330 $\Omega$	[3] [2]	30	-	kV
		1000 contact discharges (IEC 61000-4-2); OPEN Alliance specification	[2]	15	-	kV

- [1] Device stressed with 8/20 μs exponential decay waveform according to IEC 61000-4-5.
- [2] Measured from pin 1 or 2 to pin 3.
- [3] Device stressed with ten non-repetitive ESD pulses.

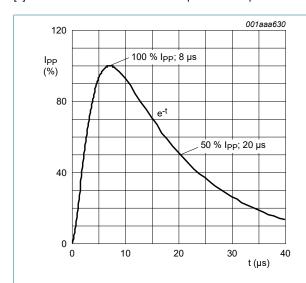


Fig. 1. 8/20 µs pulse waveform according to IEC 61000-4-5

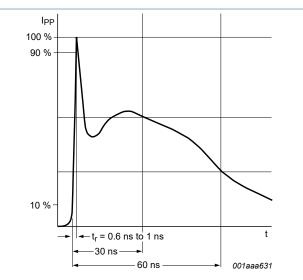


Fig. 2. ESD pulse waveform according to IEC 61000-4-2

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#### 9. Characteristics

#### **Table 6. Characteristics**

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>RWM</sub>	reverse standoff voltage	T <sub>amb</sub> = 25 °C		-	-	24	V
V <sub>h</sub>	holding voltage	t <sub>p</sub> = 100 ns; T <sub>amb</sub> = 25 °C	[1]	28	-	-	V
V <sub>t1</sub>	trigger voltage		[1]	100	130	-	V
I <sub>RM</sub>	reverse leakage current	V <sub>RWM</sub> = 24 V; V <sub>R</sub> = 0 V; T <sub>amb</sub> = 25 °C		-	1	100	nA
$C_d$	diode capacitance	f = 1 MHz; V <sub>R</sub> = 0 V; T <sub>amb</sub> = 25 °C		-	1.8	2	pF
$\Delta C_d/C_d$	diode capacitance		[2]	-	0.5	-	%
	matching	f = 1 MHz; V <sub>R</sub> = 2.5 V; T <sub>amb</sub> = 25 °C	[2]	-	0.5	-	%
R <sub>dyn</sub>	dynamic resistance	I <sub>R</sub> = 40 A; t <sub>p</sub> = 100 ns; T <sub>amb</sub> = 25 °C	[1]	-	0.6	-	Ω

- [1] Non-repetitive current pulse, Transmission Line Pulse (TLP); square pulse; ANSI / ESD STM5.5.1-2008
- [2]  $\Delta C_d$  is the difference of the capacitance measured between pin 1 and pin 3 and the capacitance measured between pin 2 and pin 3.

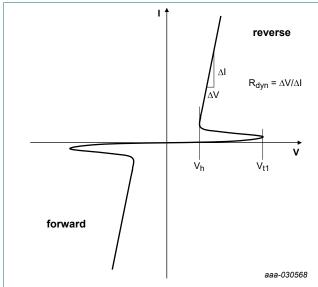


Fig. 3. V-I characteristics for a bidirectional ESD protection diode

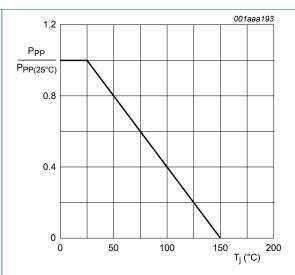


Fig. 4. Relative variation of peak pulse power as a function of junction temperature; typical values

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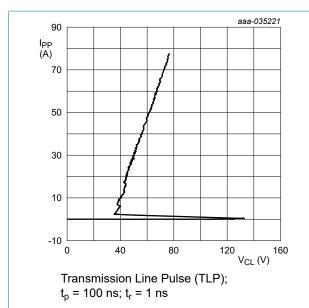


Fig. 5. Dynamic resistance with positive clamping; typical values

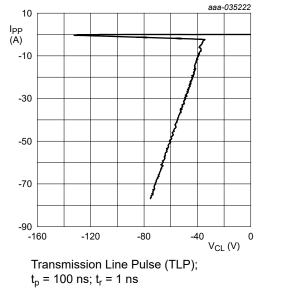
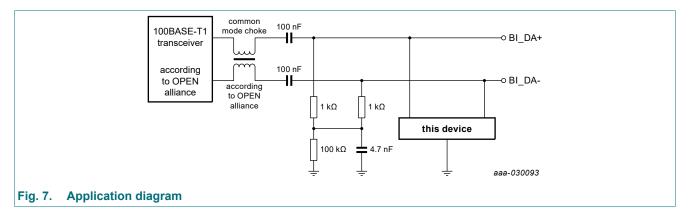


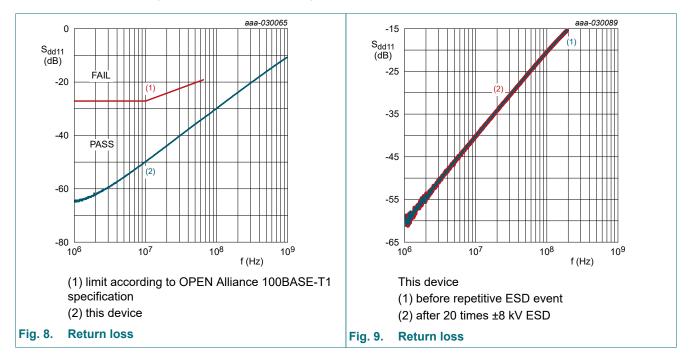
Fig. 6. Dynamic resistance with negative clamping; typical values

### 10. Application information

In the "IEEE 100BASE-T1 EMC Test Specification for ESD suppression devices" <sup>1</sup>document (further referred as OPEN Alliance 100BASE-T1 specification), the OPEN Alliance describes four different tests to ensure compliance of ESD suppressor devices and PHYs which are compliant according to the document "Transceiver EMC Test Specification". This device passes all tests as shown on figures 6 to 16. Furthermore, it complies with the requirements mentioned in Section 2.2. of "IEEE 100BASE-T1 EMC Test Specification for ESD suppression devices".



The return loss and insertion loss are evaluated using the differential S-parameters  $S_{dd11}$  and  $S_{dd21}.$  These measurements replace the requirement for a certain capacitance value. To ensure symmetry, the differential to common mode rejection is evaluated using the S-parameter  $S_{sd21}.$  This measurement replaces the requirement for a matching of the capacitances per line. To ensure that the device does not degrade and changes behavior after repetitive ESD events, the S-parameter measurements are repeated after discharging 20 times  $\pm 8$  kV ESD on signal lines 1 and 2, with C = 150 pF, R = 330  $\Omega$  according to ISO 10605. Subsequently, the S-parameters are measured again and compared to the original data.

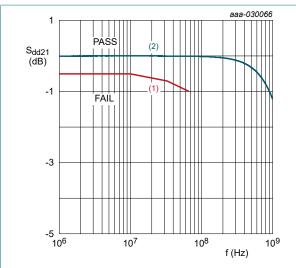


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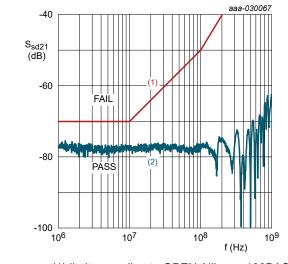
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<sup>1</sup> OPEN Alliance: "IEEE 100BASE-T1 EMC Test Specification for ESD suppression devices", version 1.0 rev. draft, December 10, 2018



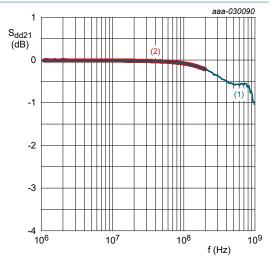
- (1) limit according to OPEN Alliance 100BASE-T1 specification
- (2) this device

Fig. 10. Insertion loss



- (1) limit according to OPEN Alliance 100BASE-T1 specification
- (2) this device

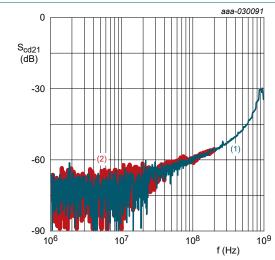
Fig. 12. Differential to common mode rejection



This device

- (1) before repetitive ESD event
- (2) after 20 times ±8 kV ESD

Fig. 11. Insertion loss

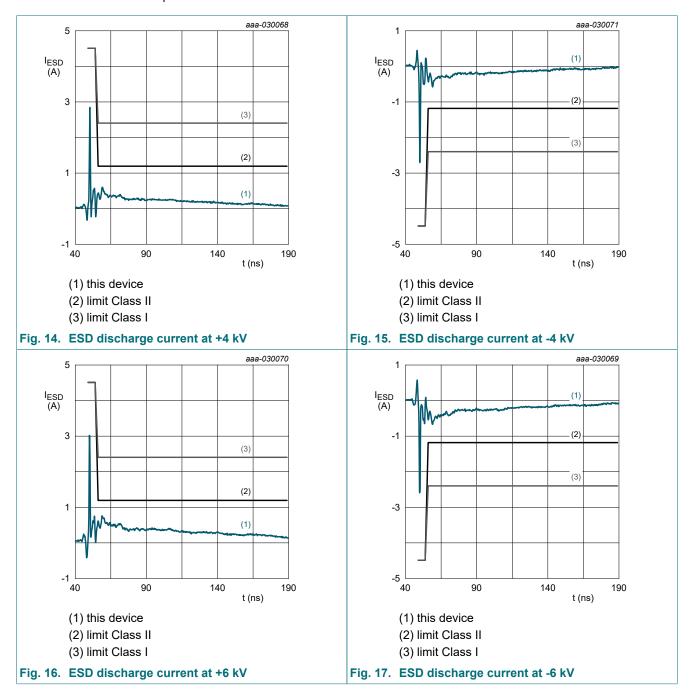


This device

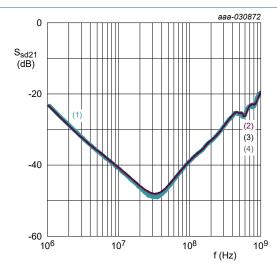
- (1) before repetitive ESD event
- (2) after 20 times ±8 kV ESD

Fig. 13. Differential to common mode rejection

To predict if the ESD suppressor device would protect a PHY of a certain robustness class (Class I (JEDEC-HBM 4 kV) and Class II (JEDEC-HBM 2 kV)), the ESD discharge current is measured in a reference circuit according to OPEN Alliance 100BASE-T1 specification for ±4 kV and ±6 kV according to IEC 61000-4-2 with C = 150 pF and R = 330  $\Omega$ . Unlike in the OPEN Alliance 100BASE-T1 specification of October 29 2017, the "Transceiver Simulation network" is implemented with 2  $\Omega$  and 50  $\Omega$  resistors.



To ensure that the ESD suppressor device is not impacting the EMC performance of the complete module, the RF clamping test as defined in the OPEN Alliance specification is applied. First a measurement at a reference power level of 25 dBm is conducted in an environment defined by the OPEN Alliance 100BASE-T1 specification. Next, the power is increased to 33 dBm (Class I), 36 dBm (Class II), and 39 dBm (Class III). No change in the measured common mode rejection indicates that the ESD suppressor device is not impacting the modules EMC performance.



According to OPEN Alliance 100BASE-T1 specification

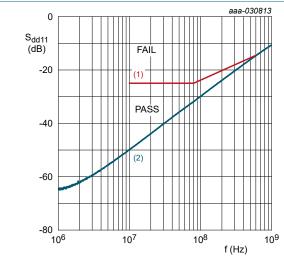
Common mode rejection for:

- (1) reference
- (2) Class I
- (3) Class II
- (4) Class III

Fig. 18. RF Clamping Test

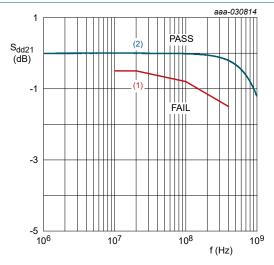
For 1000BASE-T1, there is no published document on the requirements for external ESD suppressor devices. However, a similar requirement specification is in preparation at the time the present document is created. To support the conformity of this device with the to-be-published requirement specification of OPEN Alliance for 1000BASE-T1, results of tests adapted from OPEN Alliance specification for 100BASE-T1 are shown. In this tests, limits are adapted to the current state of the art and the common-mode choke is selected in compliance with the published OPEN Alliance document "IEEE 1000BASE-T1 EMC Test Specification for Common Mode Chokes Version 1.0" as of January 16, 2018.

The following graphs show the S-parameters with adapted limit lines. ESD damage test results of 100BASE-T1 are also valid for 1000BASE-T1.



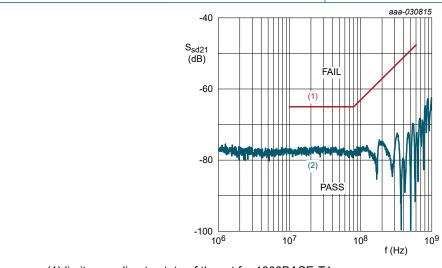
- (1) limit according to state of the art for 1000BASE-T1
- (2) this device

Fig. 19. Return loss



- (1) limit according to state of the art for 1000BASE-T1
- (2) this device

Fig. 20. Insertion loss

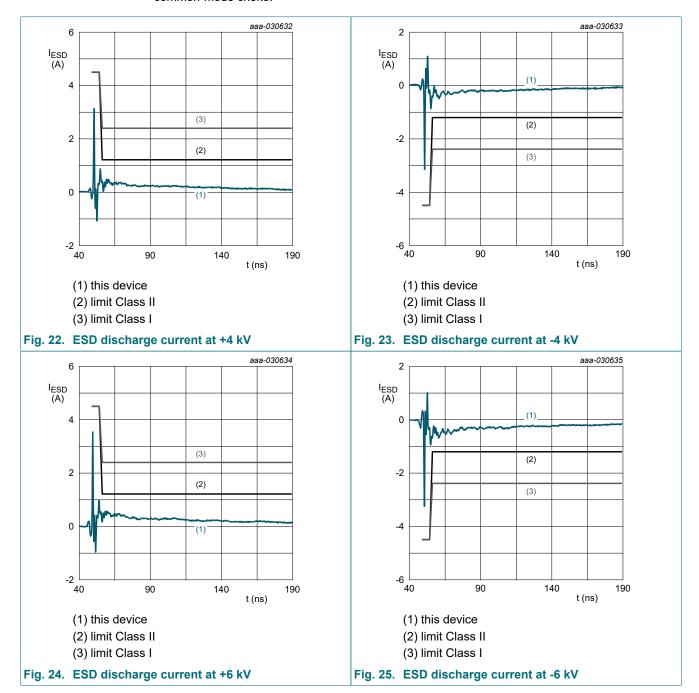


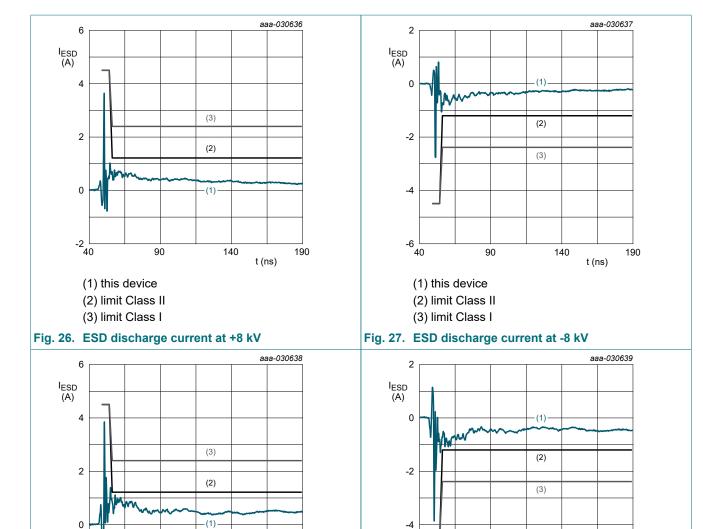
- (1) limit according to state of the art for 1000BASE-T1
- (2) this device

Fig. 21. Differential to common mode rejection

Product data sheet

The following graphs show the discharge current measurements, with a 1000BASE-T1 compliant common-mode choke.





(1) this device

- (2) limit Class II
- (3) limit Class I
- Fig. 28. ESD discharge current at +15 kV

90

140

t (ns)

190

(1) this device

-6 <sup>∟</sup>

- (2) limit Class II
- (3) limit Class I
- Fig. 29. ESD discharge current at -15 kV

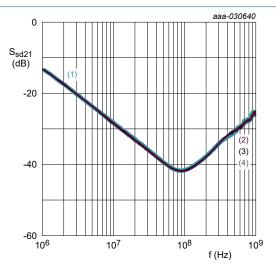
90

140

t (ns)

190

The following graph shows the RF clamping test with a 1000BASE-T1 compliant common-mode choke.



According to state of the art for 1000BASE-T1

Common mode rejection for:

- (1) reference
- (2) Class I
- (3) Class II
- (4) Class III

Fig. 30. RF Clamping Test

#### 11. Test information

#### **Quality information**

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard Q101 - *Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

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## 12. Package outline

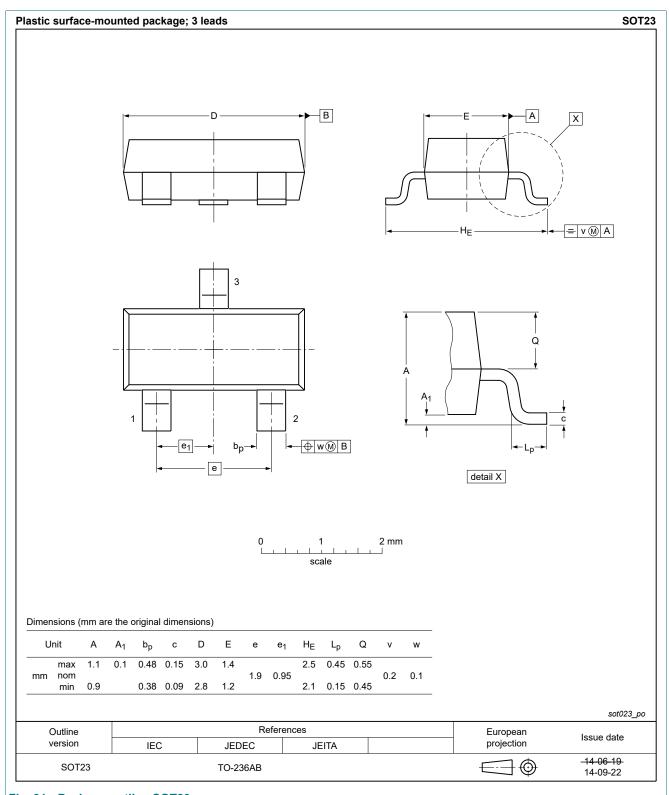
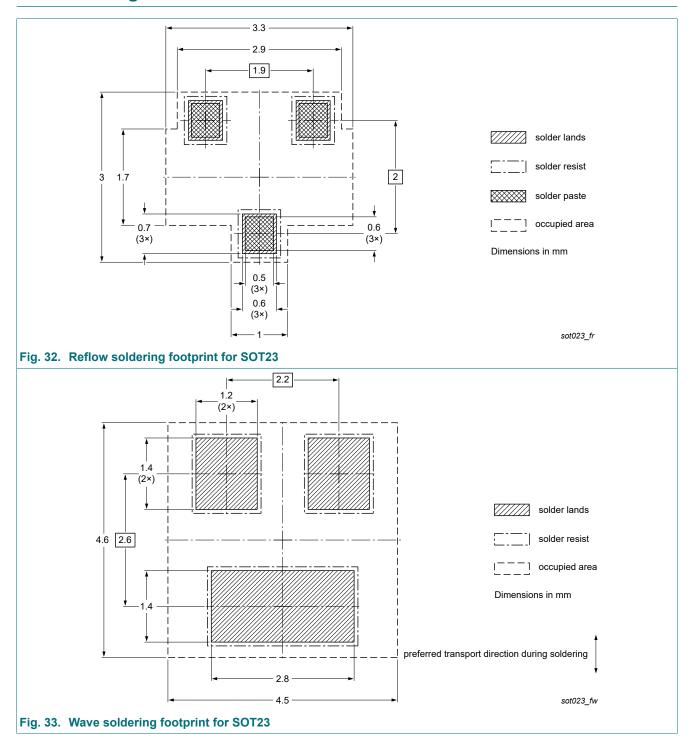


Fig. 31. Package outline SOT23

## 13. Soldering



## 14. Revision history

#### **Table 7. Revision history**

Data sheet ID	Release date	Data sheet status	Change notice	Supersedes
PESD2ETH1GT-Q v.1	20230329	Product data sheet	-	-

### 15. Legal information

#### **Data sheet status**

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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